


<b>Search Notes</b>  	<b>Application/Control No.</b>  10633418	<b>Applicant(s)/Patent Under Reexamination</b>  NAKANISHI ET AL.
	<b>Examiner</b>  Chuo, Tony	<b>Art Unit</b>  1745

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
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